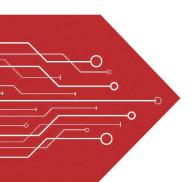
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet



FMMT449 TRANSISTOR (NPN)



SOT - 23



- 1. BASE
- 2. EMITTER
- 3. COLLECTOR

FEATURES

Low Equivalent On-Resistance

MARKING: 449

MAXIMUM RATINGS (T_a=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	50	V
V _{CEO}	Collector-Emitter Voltage	30	٧
V _{EBO}	Emitter-Base Voltage	5	V
lc	Collector Current	1	Α
Pc	Collector Power Dissipation	200	mW
$R_{\Theta JA}$	Thermal Resistance From Junction To Ambient	625	°CW
Tj	Junction Temperature	150	$^{\circ}$
T _{stg}	Storage Temperature	-55~+150	℃

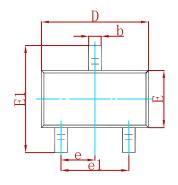
ELECTRICAL CHARACTERISTICS (Ta=25°C unless otherwise specified)

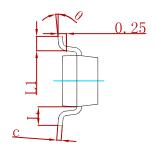
Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =1mA, I _E =0	50			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =10mA, I _B =0	30			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =100μA, I _C =0	5			V
Collector cut-off current	I _{CBO}	V _{CB} =40V, I _E =0			0.1	μA
Emitter cut-off current	I _{EBO}	V_{EB} =4 V , I_{C} =0			0.1	μA
	h _{FE(1)} *	V _{CE} =2V, I _C =50mA	70			
DC current gain	h _{FE(2)} *	V _{CE} =2V, I _C =500mA	100		300	
Do current gam	h _{FE(3)} *	V _{CE} =2V, I _C =1A	80			
	h _{FE(4)} *	V _{CE} =2V, I _C =2A	40			
Collector-emitter saturation voltage	V _{CE(sat)1} *	I _C =1A, I _B =100mA			0.5	V
Conector-entitler saturation voitage	V _{CE(sat)2} *	I _C =2A, I _B =200mA			1	V
Base-emitter saturation voltage	V _{BE(sat)} *	I _C =1A, I _B =100mA			1.25	V
Base-emitter voltage	V _{BE} *	V _{CE} =2V, I _C =1A			1	V
Transition fraguency	f_	V _{CE} =10V,I _C =50mA,	150			MHz
Transition frequency	f⊤	f=100MHz				
Collector output capacitance	C _{ob}	V _{CB} =10V, I _E =0, f=1MHz			15	pF

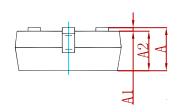
^{*}Pulse test



PACKAGE MECHANICAL DATA

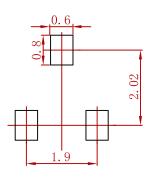






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
FMMT449	SOT-23	3000



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